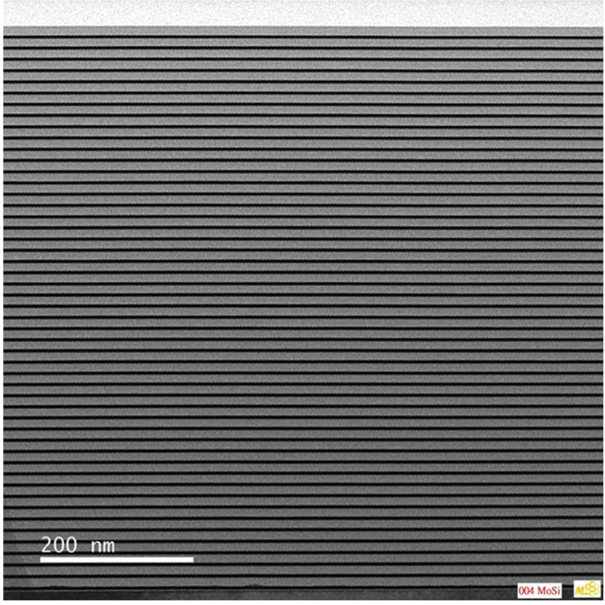

Fig. 1. Cross-sectional TEM image of the periodic Mo/Si bilayers by sputtering using cooling system.

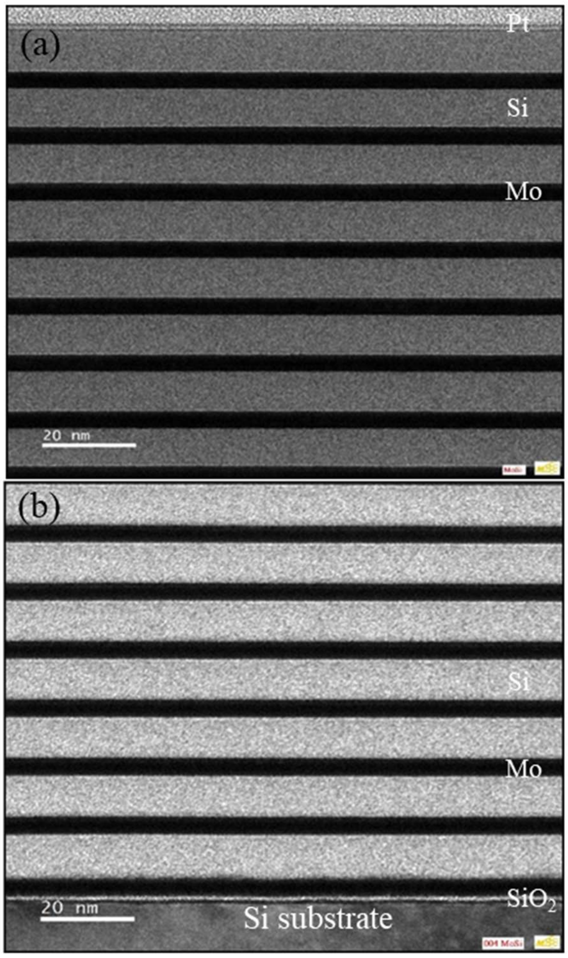

Fig. 2. Cross-sectional TEM image (a) top, and (b) bottom of the periodic Mo/Si bilayers by sputtering using cooling system.